



VISA-048

March 22, 2001

To: Commissioner of Patents and Trademarks
Washington, D.C. 20231

Fr: George O. Saile, Reg. No. 19,572
20 McIntosh Drive
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 09/764,243 01/19/01

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RETICLE OPTION LAYER DETECTION
METHOD

Grp. Art Unit: 2812

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56. Copies of each document is included herewith.

U.S. Patent 5,940,704 to Takeuchi, "Method of
Manufacturing a Reference Apparatus", discloses a method of
making a reference apparatus for determining current or voltage
in nonvolatile memory cells.

U.S. Patent 5,747,868 to Reddy et al., "Laser Fusible Link Structure for Semiconductor Devices", teaches a method to form polysilicon laser fusible links in an integrated circuit device.

U.S. Patent 4,758,863 to Nikkel, "Multi-Image Reticle", illustrates a multilevel reticle having multiple masks of integrated circuit patterns.

U.S. Patent 5,907,492 to Akram et al., "Method for Using Data Regarding Manufacturing Procedures Integrated Circuits (IC's) Have Undergone, Such As Repairs, to Select Procedures the IC's Will Undergo, Such As Additional Repairs", teaches a method for use in an integrated circuit manufacturing process.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a long horizontal flourish extending to the right.

Stephen B. Ackerman,
Reg. No. 37761